





**Figure 1**  
View of the title compound showing the labelling of non-H atoms. Displacement ellipsoids are shown at the 50% probability level.

GAMGOQ, GAMHIL, GAMHUX, GICDIF, GICDOL, JESWIN, KOMZAN, MOMSHB, NAQPIE, NEDLAJ, NITWUI, NITXAP, NORNEN, NUHCOI, NUHCUO, NUHDAV, PIBXED, PIBXIH, PIJTUX, PUCNAC, PUCNEG, RUHBOR, SOGMAC, TAJBEL, TAJBIP, TOJXUL, TOJYAS, TOJYEW, VEMVIS, VUYHIG, WARGAX, WARGEB, WARGIF, WICHAR, WICHEV, YAKCOC, YEDHUK, ZEJCAS, ZEKQEL, ZONVAZ], most probably due to the sterically demanding pentafluorophenyl substituents.

## Experimental

A toluene solution containing  $B(C_6F_5)_3$  and  $C_4H_8S$  in an approximately 1:1 ratio was slowly evaporated under an argon atmosphere over three weeks to yield colourless crystals of the adduct complex (I).

### Crystal data

$C_{22}H_8BF_{15}S$   
 $M_r = 600.15$   
 Triclinic,  $P\bar{1}$   
 $a = 9.5892$  (8) Å  
 $b = 10.8264$  (10) Å  
 $c = 11.3959$  (9) Å  
 $\alpha = 111.904$  (6)°  
 $\beta = 96.814$  (7)°  
 $\gamma = 100.727$  (7)°  
 $V = 1055.29$  (16) Å<sup>3</sup>

$Z = 2$   
 $D_x = 1.889$  Mg m<sup>-3</sup>  
 Mo  $K\alpha$  radiation  
 Cell parameters from 42 reflections  
 $\theta = 11.3$ – $12.4$ °  
 $\mu = 0.30$  mm<sup>-1</sup>  
 $T = 230$  K  
 Prism, colourless  
 $0.6 \times 0.5 \times 0.3$  mm

### Data collection

Siemens P4 diffractometer  
 $\omega$  scans  
 Absorption correction: none  
 7694 measured reflections  
 4359 independent reflections  
 3938 reflections with  $I > 2\sigma(I)$   
 $R_{int} = 0.034$

$\theta_{max} = 27.0$ °  
 $h = -10 \rightarrow 12$   
 $k = -12 \rightarrow 12$   
 $l = -14 \rightarrow 14$   
 3 standard reflections  
 every 97 reflections  
 intensity decay: 1.8%

### Refinement

Refinement on  $F^2$   
 $R[F^2 > 2\sigma(F^2)] = 0.031$   
 $wR(F^2) = 0.083$   
 $S = 1.05$   
 4359 reflections  
 384 parameters  
 All H-atom parameters refined

$w = 1/[\sigma^2(F_o^2) + (0.0271P)^2 + 0.4601P]$   
 where  $P = (F_o^2 + 2F_c^2)/3$   
 $(\Delta/\sigma)_{max} = 0.001$   
 $\Delta\rho_{max} = 0.28$  e Å<sup>-3</sup>  
 $\Delta\rho_{min} = -0.24$  e Å<sup>-3</sup>

**Table 1**

Selected geometric parameters (Å, °).

S1—C19	1.8261 (15)	B1—C13	1.624 (2)
S1—C22	1.8286 (18)	B1—C7	1.628 (2)
S1—B1	2.0843 (16)	B1—C1	1.628 (2)
C13—B1—C7	115.42 (12)	C13—B1—S1	106.45 (10)
C13—B1—C1	113.86 (12)	C7—B1—S1	101.67 (9)
C7—B1—C1	112.10 (12)	C1—B1—S1	105.93 (9)

A relatively low data completeness (94.6%) was caused by the presence of a cooling device. The C—H bond lengths are 0.94 (2)–1.02 (2) Å.

Data collection: *XSCANS* (Siemens, 1992); cell refinement: *XSCANS*; data reduction: *XSCANS*; program(s) used to solve structure: *SHELXS97* (Sheldrick, 1997); program(s) used to refine structure: *SHELXL97* (Sheldrick, 1997); molecular graphics: *SHELXTL-Plus* (Siemens, 1991); software used to prepare material for publication: *SHELXL97*.

## References

- Allen, F. H. & Kennard, O. (1993). *Chem. Des. Autom. News*, **8**, 31–37.  
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